observing an interference pattern of the thus obtained superimposed light beam to analyze anisotropy of the sample.

2. (Amended) The method as defined in claim 1, wherein the given angle is 90 degrees.

3. (Amended) The method as defined in claim 1, comprising the step of superimposing the two light beams before introducing into the sample, whereby the thus obtained superimposed light beam is introduced into the sample.

4. (Amended) The method as defined in claim 3, wherein the given angle is 90 degrees.

5. (Amended) The method as defined in claim 1, wherein the two light beams are introduced into the sample so that their beam directions are crossed.

6. (Amended) The method as defined in claim 5, wherein the given angle is 90 degrees.

7. (Amended) A method for analyzing anisotropy of a sample comprising the steps of:

preparing a single polarized light beam,

introducing the single polarized light beam into a sample to be measured in anisotropy,

dividing the single polarized light beam into two light beams, after passing through the sample,

superimposing the two divided light beams, and

observing an interference pattern of the thus obtained superimposed light beam to analyze anisotropy of the sample.

8. (Amended) An apparatus for analyzing anisotropy of a sample comprising:

,before a sample to be measured in anisotropy,

a laser source to generate and oscillate a light beam to be used in anisotropy analysis,

a light beam-dividing means to divide a light beam from the laser source into two light beams, and

a first plane of polarization-rotating means to rotate the plane of polarization of one of the thus obtained two divided light beams by a given angle,

,after the sample to be measured in anisotropy,

a second plane of polarization-rotating means to rotate the plane of polarization of the one or the other of the two divided light beams by the given angle so that their planes of polarization can correspond each other,

a light beam-superimposing means to superimpose the two divided light beams, and

a light beam-projecting means to project and observe an interference pattern of the thus obtained superimposed light beam.

9. (Amended) The apparatus as defined in claim 8, wherein at least one of the first and the second plane of polarization-rotating means is composed of a half-wave plate.

10. (Amended) The apparatus as defined in claim 8, wherein at least one of the light beam-dividing means and the light beam-superimposing means is composed of a half mirror.

11. (Amended) The apparatus as defined in claim 8, further comprising:

,before the sample to be measured in anisotropy, another light beam-superimposing means to superimpose the two divided light beams after the first plane of polarization-rotating means

,after the sample to be measured in anisotropy, a light beam-splitting means to split the superimposed light beam before the second plane of polarization-rotating means.

12. (Amended) The apparatus as defined in claim 11, wherein at least one of the first and the second plane of polarization-rotating means is composed of a half-wave plate.

13. (Amended) The apparatus as defined in claim 11, wherein at least one of the light beam-dividing means and the light beam-superimposing means is composed of a half mirror.

14. (Amended) The apparatus as defined in claim 11, wherein the another light beam-superimposing means is composed of a half mirror.

15. (Amended) The apparatus as defined in claim 11, wherein the light beam-splitting means is composed of a polarized light beam splitter.

REMARKS

The claims have been amended to clarify the invention or correct minor informalities. Attached hereto is a marked-up version of the changes made to the claims by the current amendment. The attached page is captioned "VERSION WITH MARKINGS TO SHOW CHANGES MADE." The amendments do not constitute the addition of any new matter to the